

TO:	文件编号	HXA-L30-12(01)
10:	发行日期	2020年04月22日

承认规格书

种类: 功率电感

系列号: <u>HCDH4D28N-1R8M</u>

客户料号:_____

李	好户 承 认 栏			
承认日期	年	月	日	

(贵司承认后请签署一份返回华信安电子,谢谢!)

厦门华信安电子科技有限公司技术质量部

承 认	确认	作成
龙梅	梁峰	王亮

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Power Inductor

HCDH4D28N-1R8M

		ECN HISTORY	LIST		
REV	DATE	DESCRIPTION	APPROVED	CHECKED	DRAWN
1.0	20/04/22	新 發 行	龙梅	梁峰	王亮
備					
註					

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ISND P2

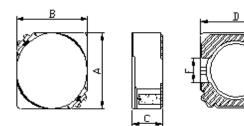
Power Inductor

HCDH4D28N-1R8M

1. Features

- 1. This specification applies Low Profile Power Inductors.
- 2. 100% Lead(Pb) & Halogen-Free and RoHS compliant.

2. Dimension

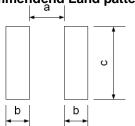


Series	A(mm)	B(mm)	C(mm)	D(mm)	E(mm)	F(mm)
HCDH4D28N	4.7±0.3	4.7±0.3	3.0MAX	4.5	4.5	1.5





Recommendend Land pattern



a(mm)	b(mm)	c(mm)
1.5 TYP	1.9 TYP	5.3 TYP

3. Part Numbering

HCDH 4D28 N - 1R8 M

- A: Series
- B: Dimension
- C: Control S/N

D: Inductance 1R8=1.8uH
E: Inductance Tolerance M=±20%

4. Specification

ISND	Inductance	Tolerance	Test Frequency	DCR	l sat	I rms
Part Number	(uH)	(%)	(Hz)	(Ω) Max	(A)	(A)
HCDH4D28N-1R8M	1.8	±20%	0.25V100K	0.031	2.20	2.20

Note:

Isat : Based on inductance change $\,$ (${\scriptstyle \triangle}\text{L/L0}$: $\leqq\text{-35\%}$) @ ambient temp. 25°C

Irms : Based on temperature rise $\,$ ($^{\vartriangle}T$: 40°C $\,$ typ.)

_ISND P3

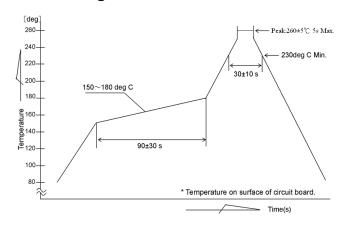
5. Reliability and Test Condition

ltem	Performance	Test Method and Remarks
Operating Temperature	- 40 ~ +125°C.	Including self-generated heat
Storage Temperature	-40 ~ +85°C. -5 to 40°C for the product with taping.	
Rated current		
Inductance (L)	Within the specified tolerance	LCR Meter: HP 4285A or equivalent, 100kHz, 0.25V
DC Resistance		DC Ohmmeter: HIOKI3227 or equivalent
Temperature characteristics	Inductance change: Within±20%	Measurement of inductance shall be taken at temperature rang within–40°C to +85°C. With reference to inductance value at+20 °C,change rate shall be calculated. Measurement of inductance shall be taken at temperature rang within–40°C to +125°C. With reference to inductance value at+20 °C,change rate shall be calculated.
Resistance to flexure substrate	No damage.	The test samples shall be soldered to the testing board by the reflow. As illustrated below, apply force in the direction of the arrow indicating until deflection of the test board reaches to 2mm. Force 1 20 1 20 1 20 1 20 1 20 1 20 1 20 1 2
Adhesion of Terminal electrode	Shall not come off PC board.	The test samples shall be soldered to the testing board and by the reflow. 10 N, 5 s Applied force: 10 N to X and Y directions. Duration: 5s Solder cream thickness: 0.15
Resistance to Vibration	Inductance change: Within±10% No abnormality observed in appearance.	The test samples shall be soldered to the test board by the reflow. Then it shall be submitted to below test conditions. Frequency: 10-55Hz Total Amplitude: 1.5mm (May not exceed acceleration 196m/S2) Sweeping Method:10Hz to 55Hz to 10Hz for 1min. Time: 2 hours each in X,Y, and Z Direction. Recovery: At least 2hrs of recovery under the standard condition after the test, followed by the measurement within 48hrs.
Solderability	At least 90% of surface of terminal electrode is covered by new solder.	The test samples shall be dipped in flux, and then immersed in molten solder as shown in below. Flux: methanol solution containing rosin 25% Solder temperature: 245 ± 5 °C Time: 5 ± 1.0 sec. Immersion depth: All sides of mounting terminal shall be immersed.

_ISND P4

Item	Performance		Test Method and Re	emarks	
Resistance to soldering		for 40 second seconds,2 tim Test board thi	ole shall be exposed to ls, with peak temperatu les. ickness: 1.0mm aterial: glass epoxy-res	re at 260±5°C for	
		reflow. The test samp for specified t sequence.	oles shall be soldered to oles shall be placed at s ime by step 1 to step 4 ure cycles shall be repe	specified tempera as shown below i	ture n
Thermal shock		Phase	Temperature(℃)	Time(min.)	
		1	-40±3℃	30±3	
		2	RoomTemp	Within 3	
		3	85±2℃	30±3	
		4	RoomTemp	Within 3	
Damp heat life test	Inductance change: Within±10% No abnormality observed in appearance.	Test Method and Remarks The test samples shall soldered to the test board by the reflow. The test samples shall be placed in thermostatic or specified temperature and humidity as shown in be Temperature: 60±2°C Humidity: 90-95%RH Time: 500+24/-0 hrs			
Loading under damp heat life test		reflow. The test samp specified tem current contin Temperature: Humidity: 90-	-95%RH nt: Rated current	hermostatic oven and applied the ra	set at
Low temperature life test		reflow.	-40±2℃		
Loading at high temperature life test		reflow. Temperature:	nt: Rated current	o the test board b	y the

6. Soldering

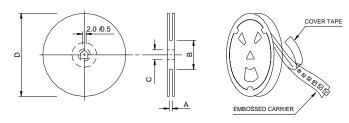


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<u>ISND</u> P5

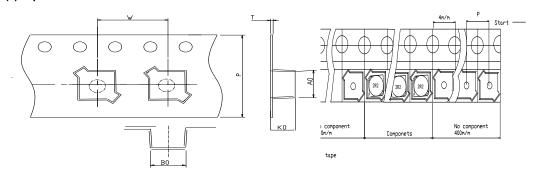
7. Packaging Information

(1) Reel Dimension



Туре	A(mm)	B(mm)	C(mm)	D(mm)
HCDH4D28N	16.4±0.2	100±4.0	13.2±0.2	330±2.0

(2) Tape Dimension



Туре	Ao(mm)	Bo(mm)	Ko(mm)	P(mm)	W(mm)	t(mm)
HCDH4D28N	5.3±0.1	5.3±0.1	3.1±0.1	12.0±0.1	16±0.3	0.4±0.05

(3) Packaging Quantity

Туре	Chip / Reel
HCDH4D28N	2000

Application Notice

·Storage Conditions

- To maintain the solderability of terminal electrodes:
- 1. ISND products meet IPC/JEDEC J-STD-020D standard-MSL, level 1.
- 2. Temperature and humidity conditions: Less than 40°C and 60% RH.
- 3. Recommended products should be used within 12 months form the time of delivery.
- 4. The packaging material should be kept where no chlorine or sulfur exists in the air.

Transportation

- 1. Products should be handled with care to avoid damage or contamination from perspiration and skin oils.
- 2. The use of tweezers or vacuum pick up is strongly recommended for individual components.
- 3. Bulk handling should ensure that abrasion and mechanical shock are minimized.

单击下面可查看定价,库存,交付和生命周期等信息

>>ISND(华信安)